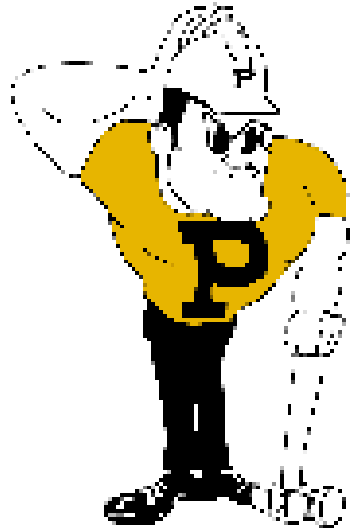


Scanning Probe Microscopy for Medical Applications

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Birck Nanotechnology Center
Bindley Biosciences Center
Purdue University



IEEE Central Indiana Section
EnCON
11 November 2017

PURDUE
POLYTECHNIC

Birck Nanotechnology Center

Discovery Park

Bindley Bioscience Center

Outline

Basics of Scanning Probe Microscopy

SPM Integration and Optimization for Medical Applications

Neuroscience and other applications

Force Microscopy – Modified Lateral

Hyperbaric AFM Development

Magnetic and Electric Force Microscopy

Summary with Discussion

QUESTIONS?

Scanning Probe Microscopy (SPM)

- Scanning Tunneling Microscopy – Rohrer and Binnig 1982
- Atomic Force Microscopy (AFM/SFM) – Binnig et al 1986

Resolution:

Optical – 200nm

AFM – atomic resolution *possible*
– tip dimension, detection system,
operating conditions & controls

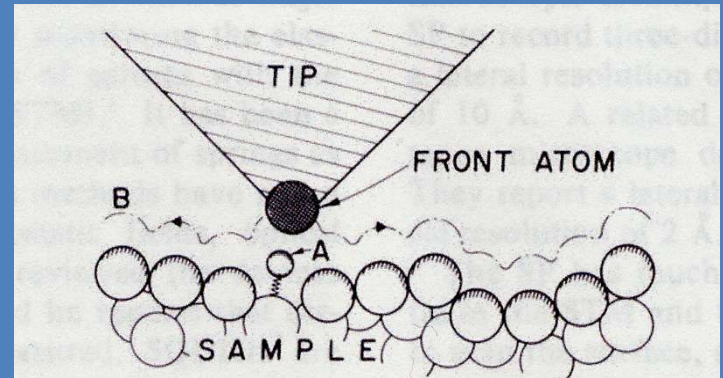
Measurement Capabilities:

Topography *and*
Material Characteristics
mechanical
electrical
chemical.....

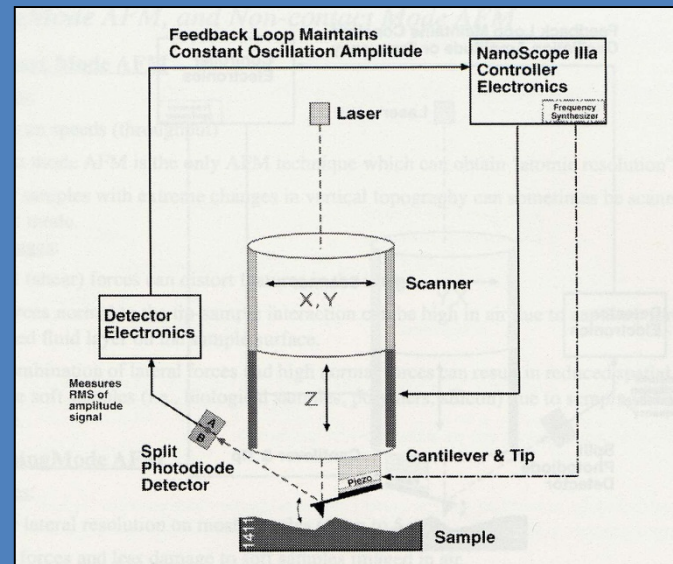
Operating Conditions:

Vacuum, air (gas), liquid,
and now in hyperbaric conditions

D'Agostino, D., McNally, H.A., & Dean, J.B., (2012).
Hyperbaric atomic force microscopy. Journal of Microscopy, 246, (2), 129-142.*



Principle of Operation,
Binnig, G., Quate, C.F., & Gerber, Ch., *Atomic Force Microscopy*,
Physics Review Letts, 1986, Vol. 56, No. 9, pp. 930-933.



Other Established Types of Scanning Probe Microscopy

CFM, chemical force microscopy

C-AFM, conductive atomic force microscopy

ECSTM electrochemical scanning tunneling microscope

EFM, electrostatic force microscopy

FMM, force modulation microscopy

FOSPM, feature-oriented scanning probe microscopy

KPFM, kelvin probe force microscopy

MFM, magnetic force microscopy

MRFM, magnetic resonance force microscopy

NSOM, near-field scanning optical microscopy (or SNOM, scanning near-field optical microscopy)

PFM, Piezoresponse Force Microscopy

SCM, scanning capacitance microscopy

SECM, scanning electrochemical microscopy

SHPM, scanning Hall probe microscopy

SICM, scanning ion-conductance microscopy

SPSM spin polarized scanning tunneling microscopy

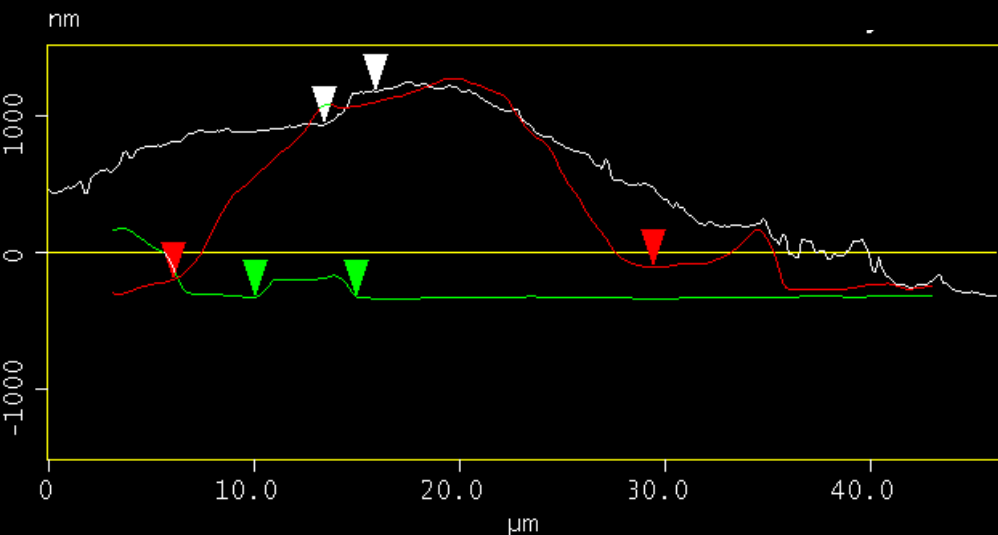
SSM, scanning SQUID microscopy

SSRM, scanning spreading resistance microscopy

SThM, scanning thermal microscopy

STP, scanning tunneling potentiometry

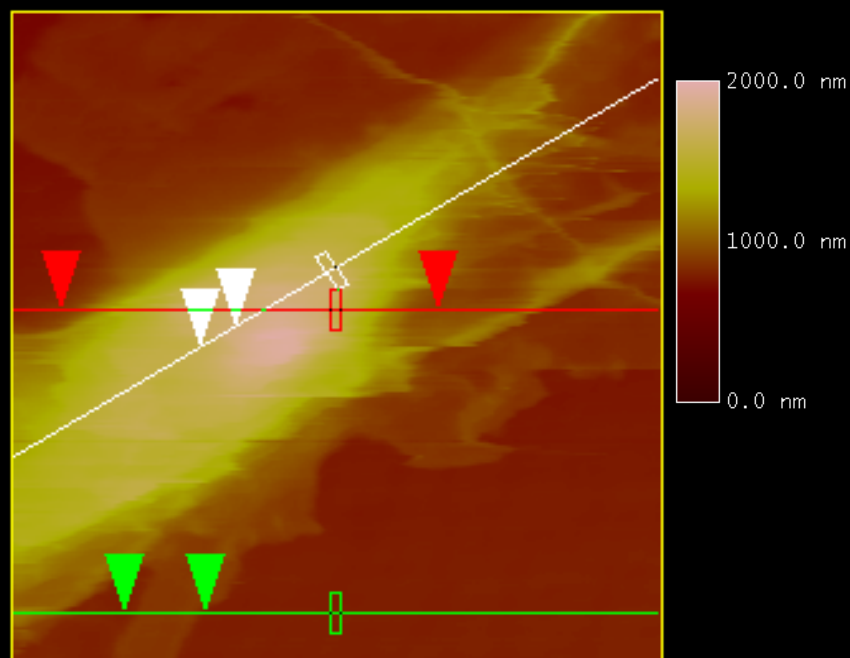
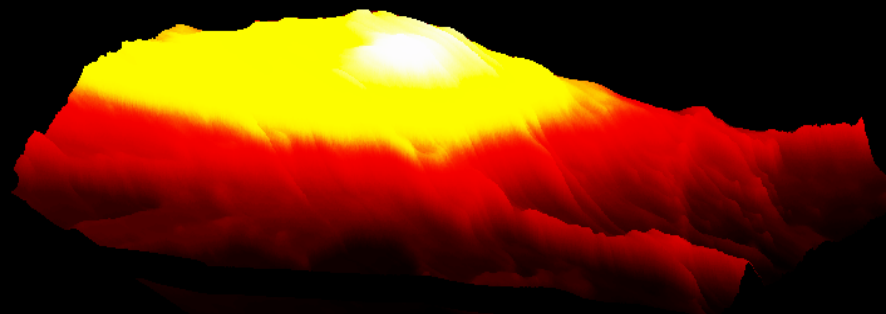
SVM, scanning voltage microscopy



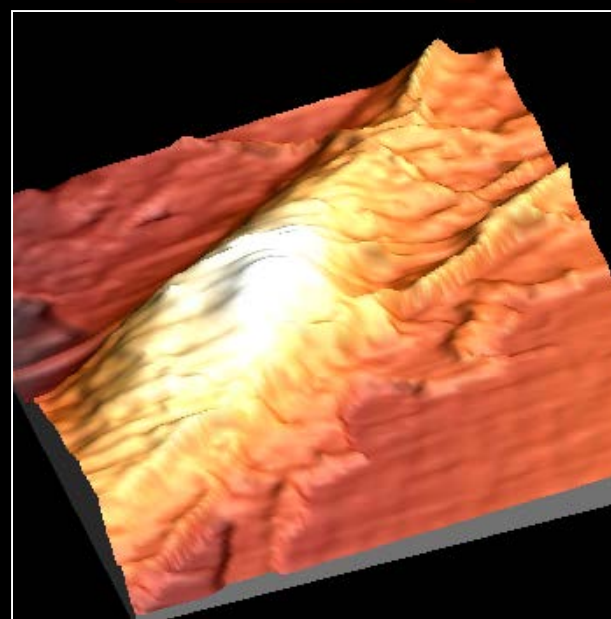
Cell Body Parameters

10X20 μm in diameter

1-4 μm high



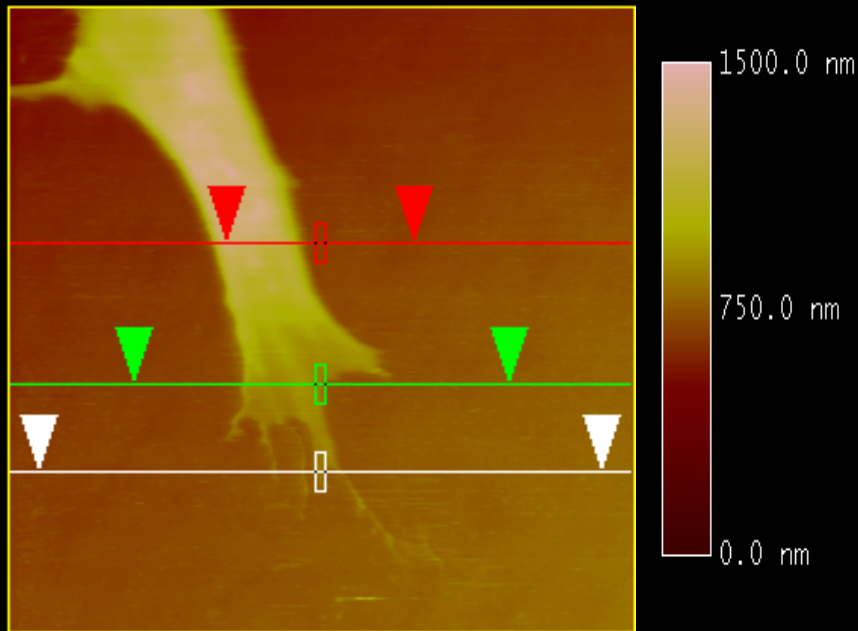
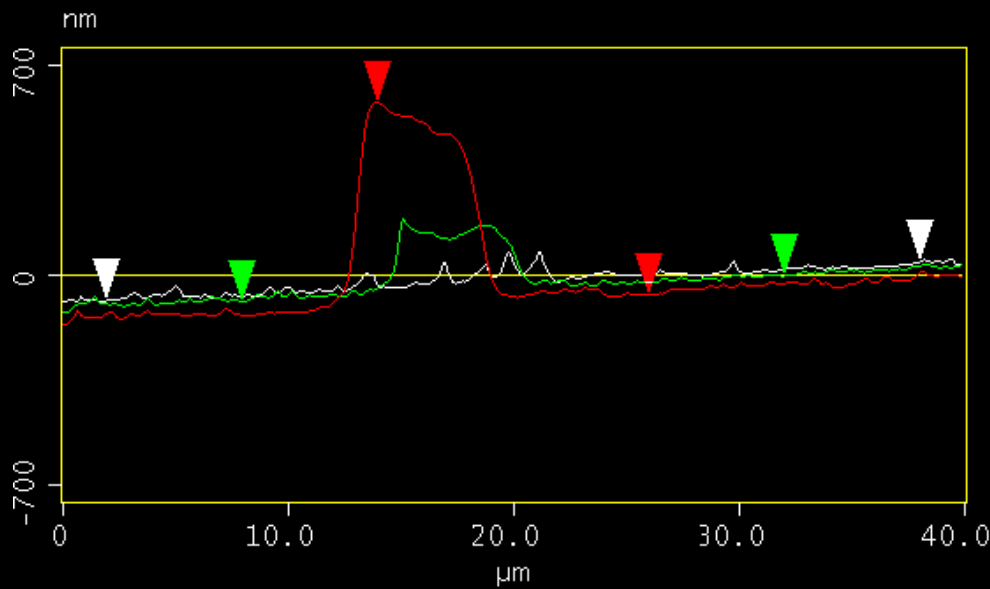
Height Mode Image



3-D Reconstruction

Growing Process Parameters

Neurite: $6.03 \pm 2.1 \mu\text{m}$ wide and $385.1 \pm 192.7 \text{ nm}$ high with vertical projections of $94.87 \pm 70.2 \text{ nm}$, $n=15$
Growth Cone: $10.3 \pm 2.89 \mu\text{m}$ wide and $260.4 \pm 176 \text{ nm}$ high with vertical projections averaging $258.5 \pm 148.6 \text{ nm}$, $n=15$
Axonal Spines: ranged in caliber from 100 nm to $1 \mu\text{m}$ and $1 - 2 \mu\text{m}$ in length, $n=5$

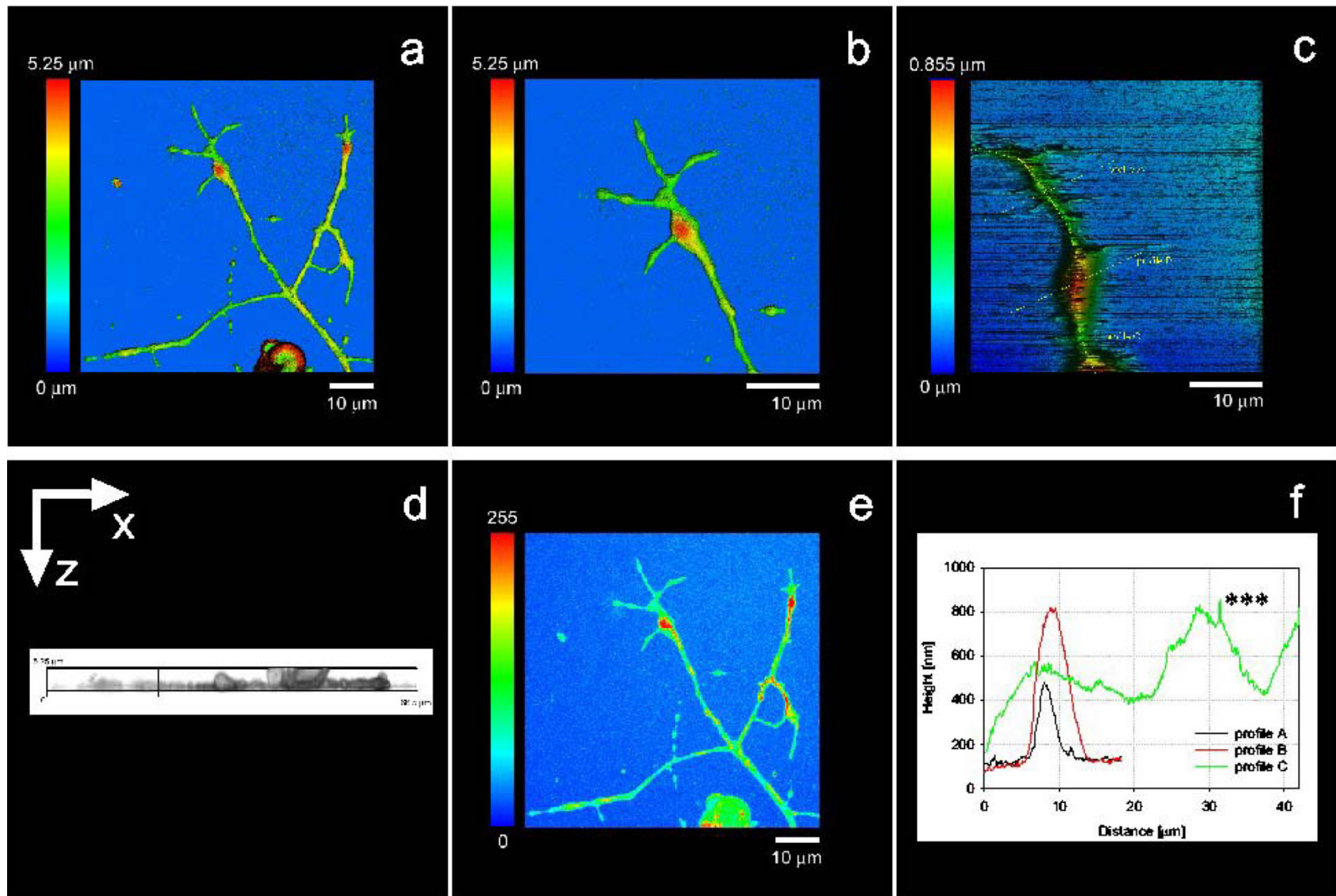


Height Mode Image



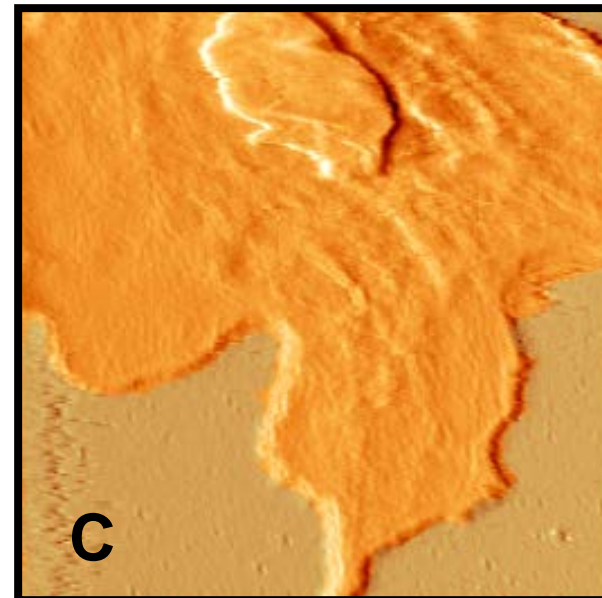
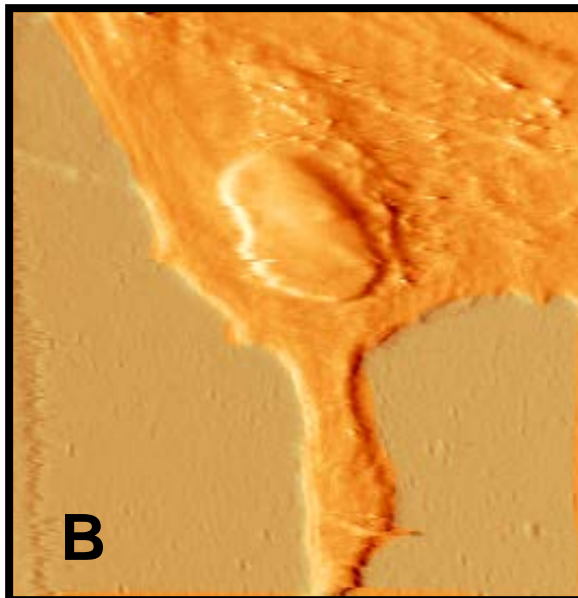
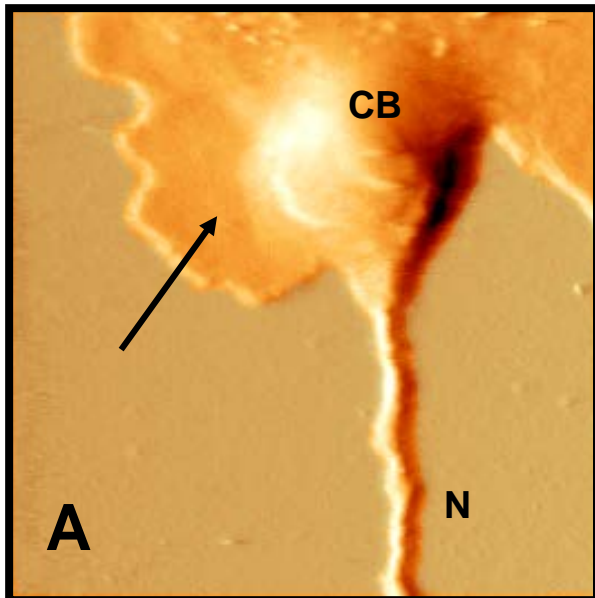
3-D Reconstruction

AFM Compared to Confocal Microscopy

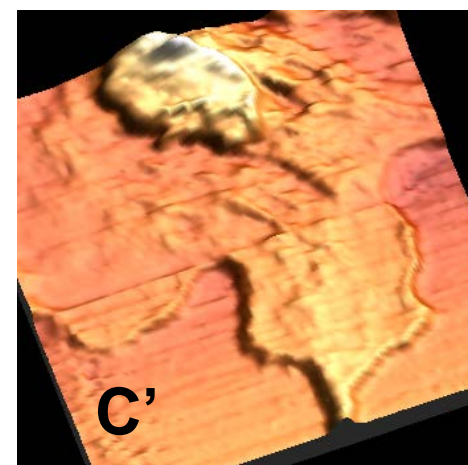
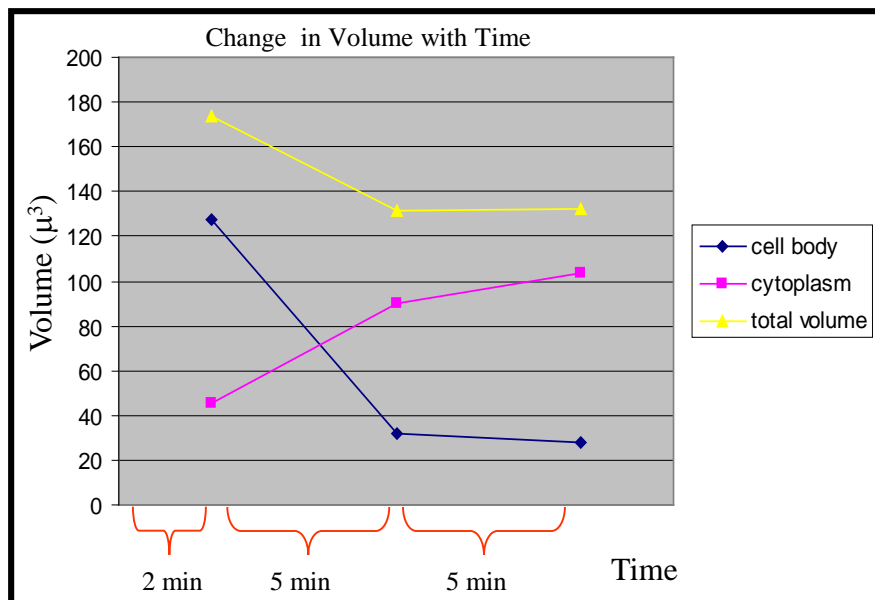
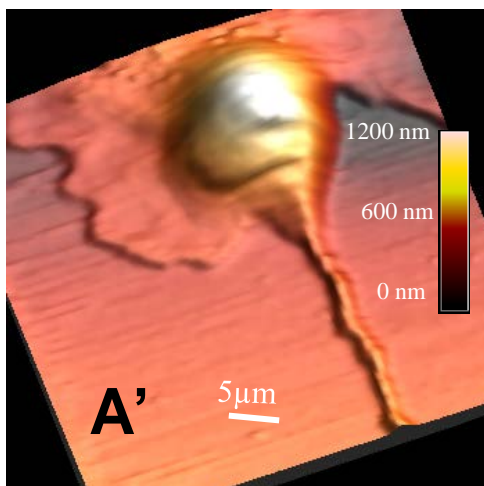


H.McNally, B. Rajwa, J. Sturgis, and J.P. Robinson, "Living Neuron Morphology Imaged with Atomic Force Microscopy and Confocal Microscopy" *Journal of Neuroscience Methods*, V. 142 (2005) pp.177-184.

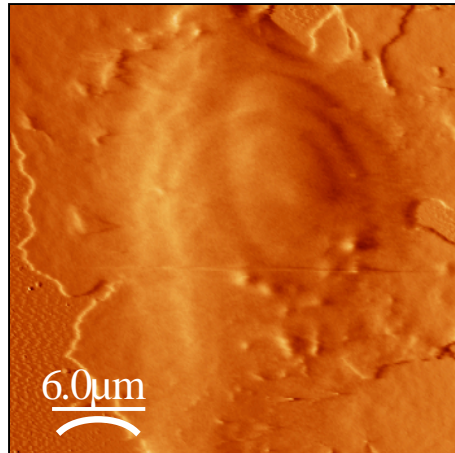
Cell Death by AFM Probe



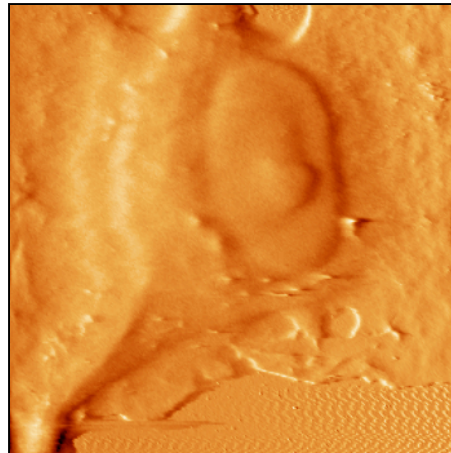
time →



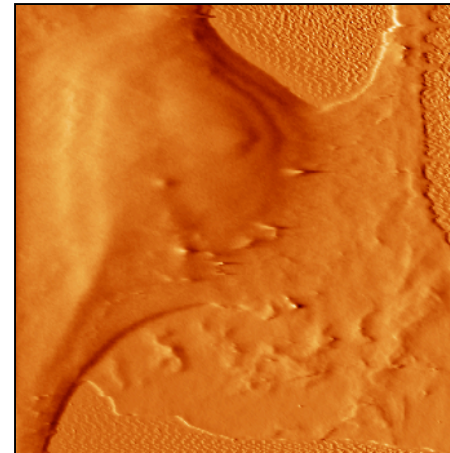
Effects of Endotoxin - Acrolein



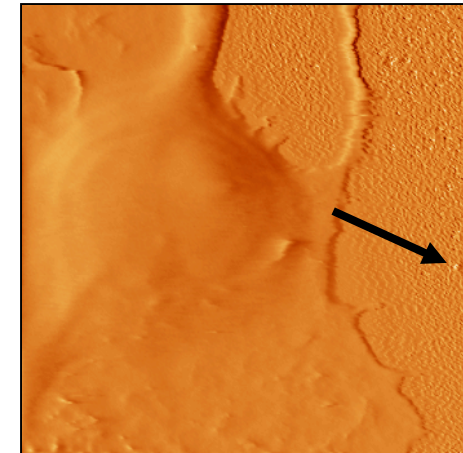
Prior to acrolein



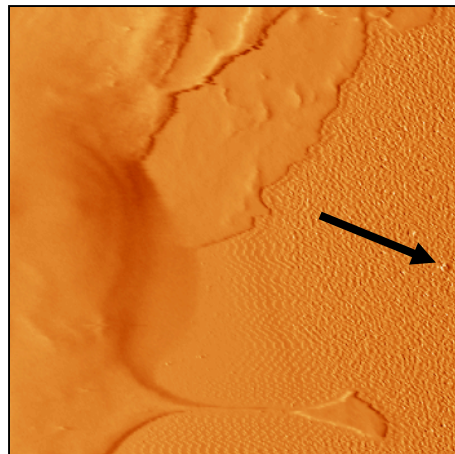
T+15min



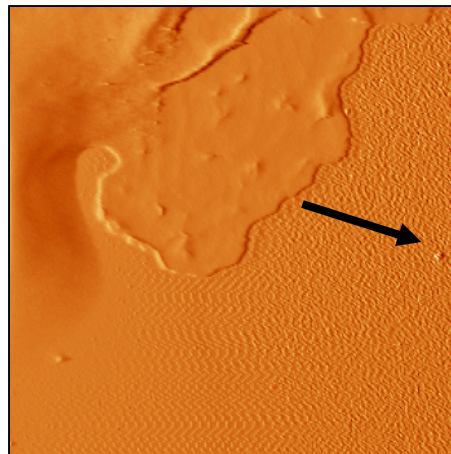
T+35min



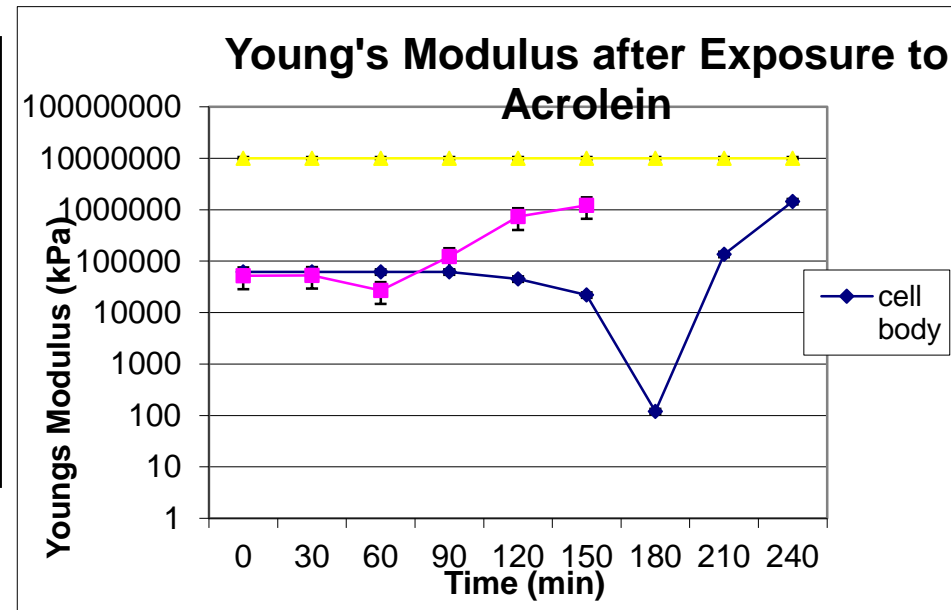
T+55min



T+1hr,15min

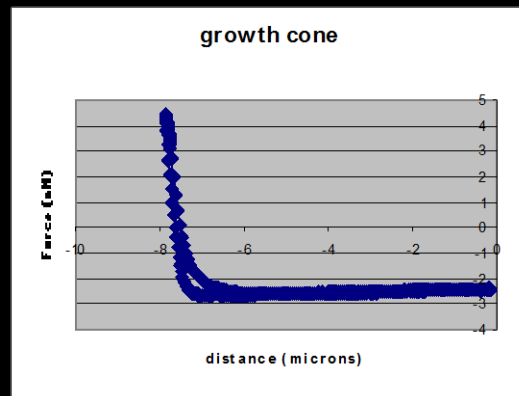
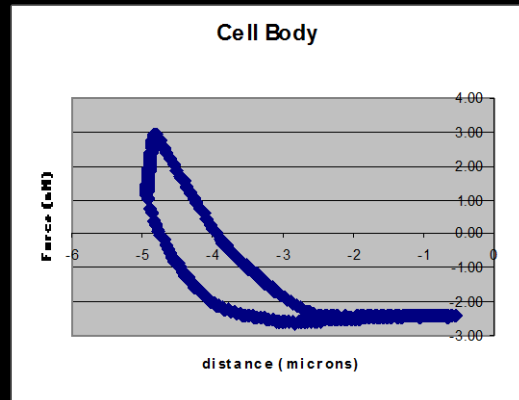
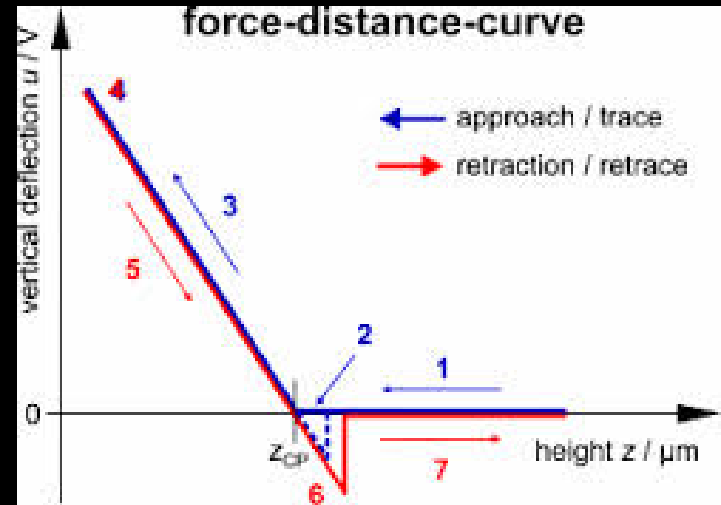
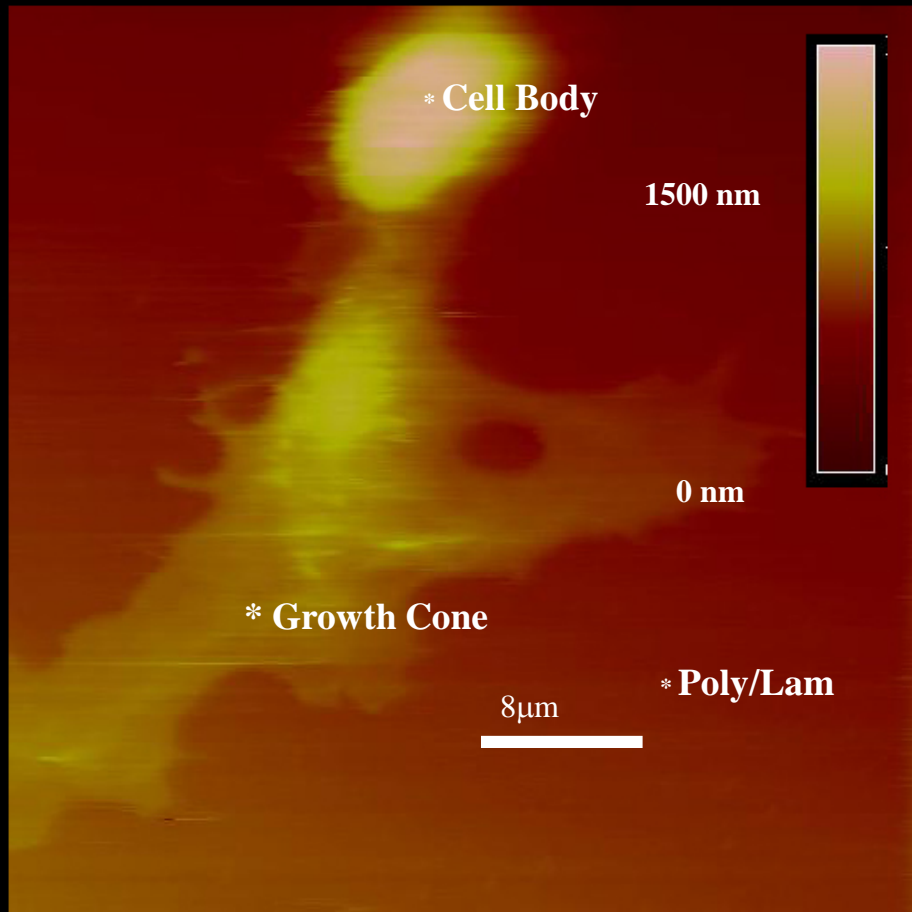


T+1hr,25min



P. Liu-Snyder, H. McNally, R. Shi, R. Borgens, "Acrolein-Mediated Mechanisms of Neuronal Death", Journal of Neuroscience Research, V.84, pp.209-218, (2006)

Force Measurements – Membrane Elasticity

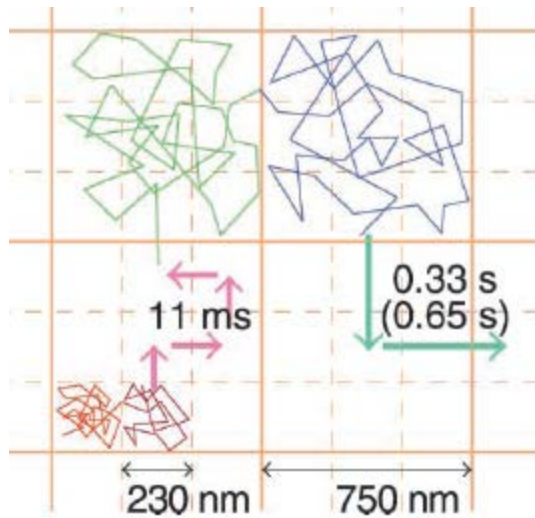


Average Elasticity
 Cell Body: 60KPa
 Growth Cone: unknown

Probing Cellular Membrane Structure and Elasticity with Atomic Force Microscope

Mirela Mustata, Helen McNally, Ken Ritchie

The goal of this project is to probe the cellular membrane and underlying cytoskeleton using AFM to understand the mechanical properties of the cell and especially the structure of the ultrafine compartments of cytoskeleton underlying the cellular membrane. Previous research on neurons show that the composition and biochemical properties of the cytoskeleton differ in the neuron cell body from the properties of the cytoskeleton associated with the axon.



SINGLE PARTICLE TRACKING

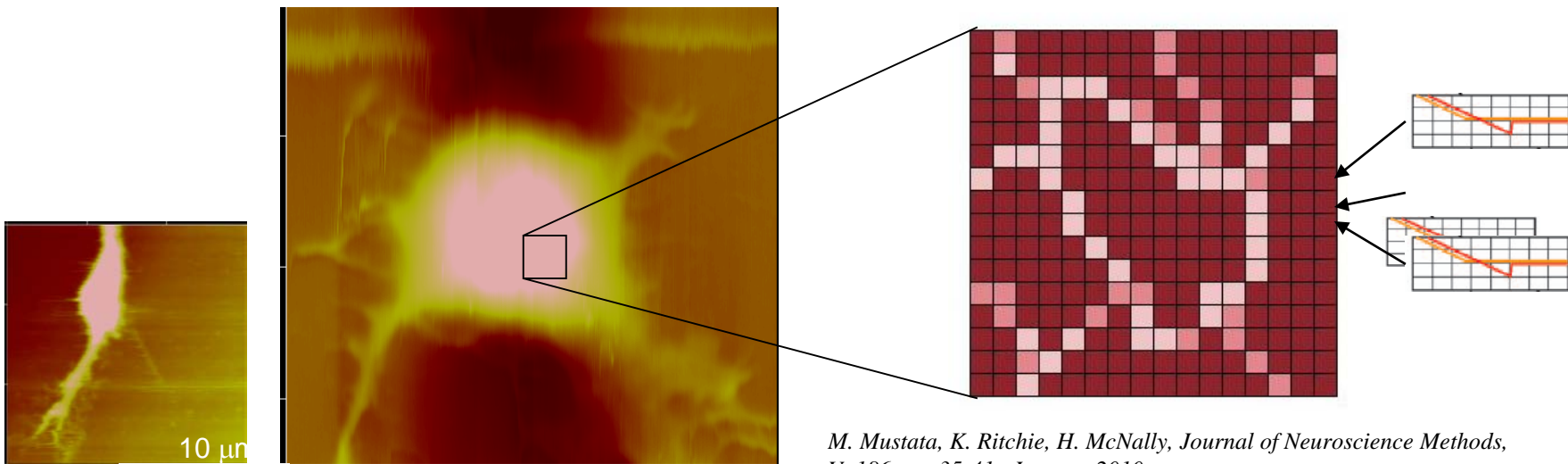
double compartments in NRK cells.

(DOPE) undergoes diffusion inside a 230 nm compartment for 11 ms and then hops to an adjacent compartment. In the 750 nm compartments the residence time is much larger (of about 330 ms)

Fujiwara, et al. (2002) Journal of Cell Biology, 157, No. 6, 1071-1081

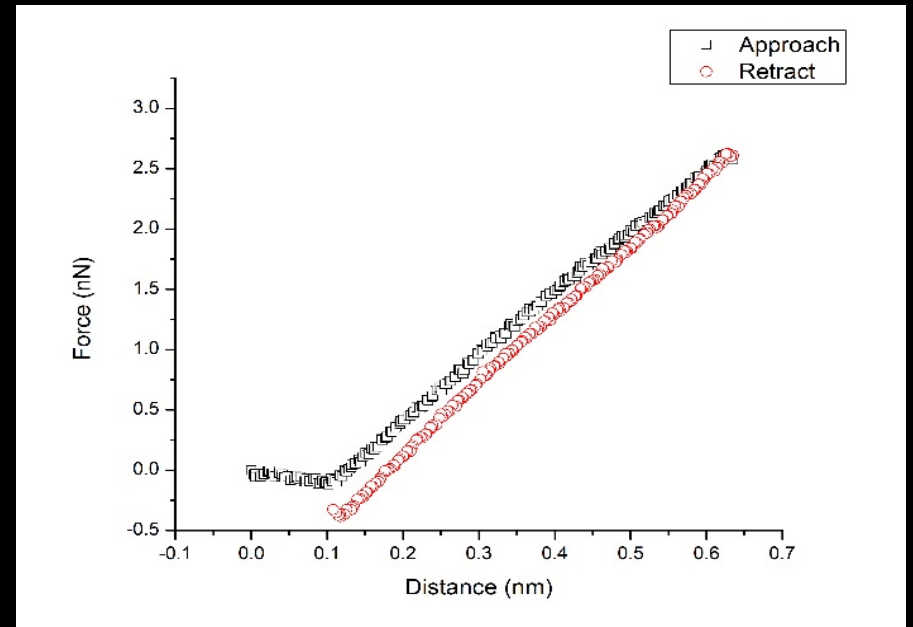
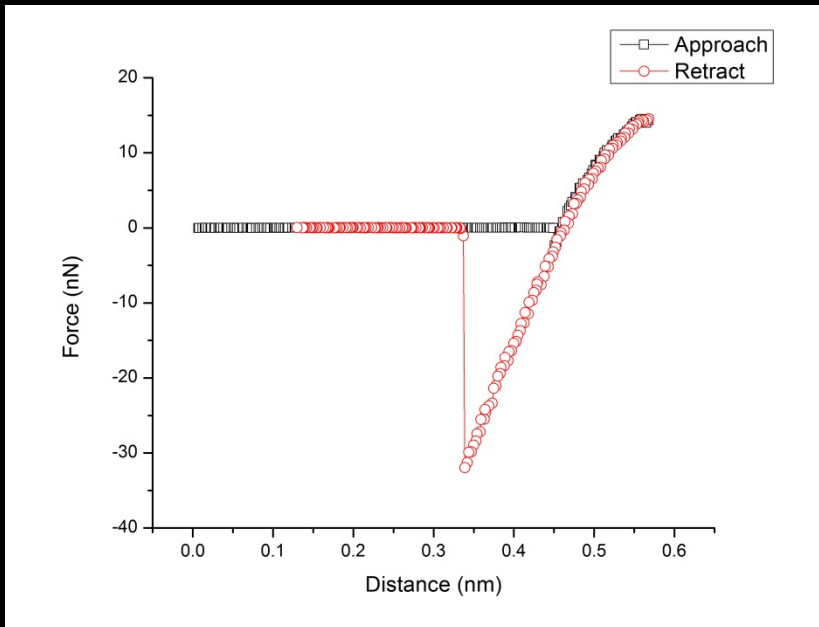
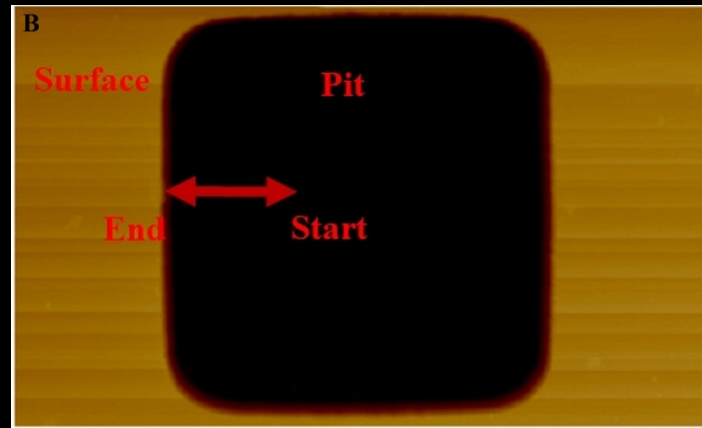
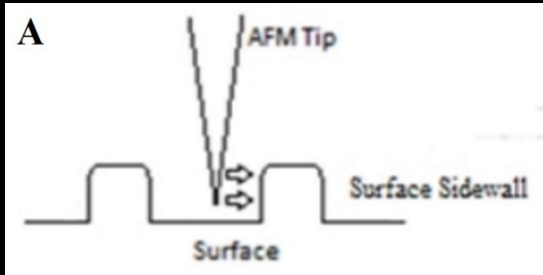


Force Volume of a 16X16 pixel surface (simulation) each pixel representing the cantilever deflection versus Z piezo position. Brighter spots correspond to higher stiffness points (actin filaments underlying the membrane)



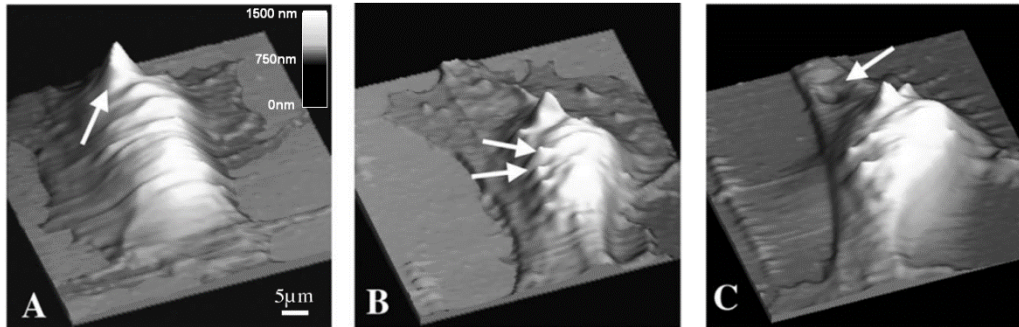
M. Mustata, K. Ritchie, H. McNally, *Journal of Neuroscience Methods*, V. 186, pp.35-41., January 2010

Measuring Membrane Viscosity with a Modified Lateral Force Technique



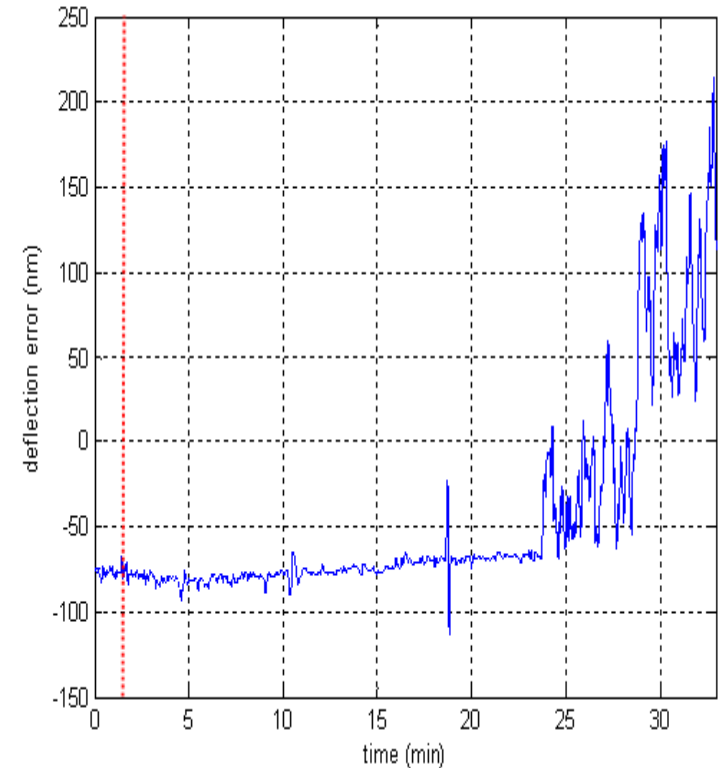
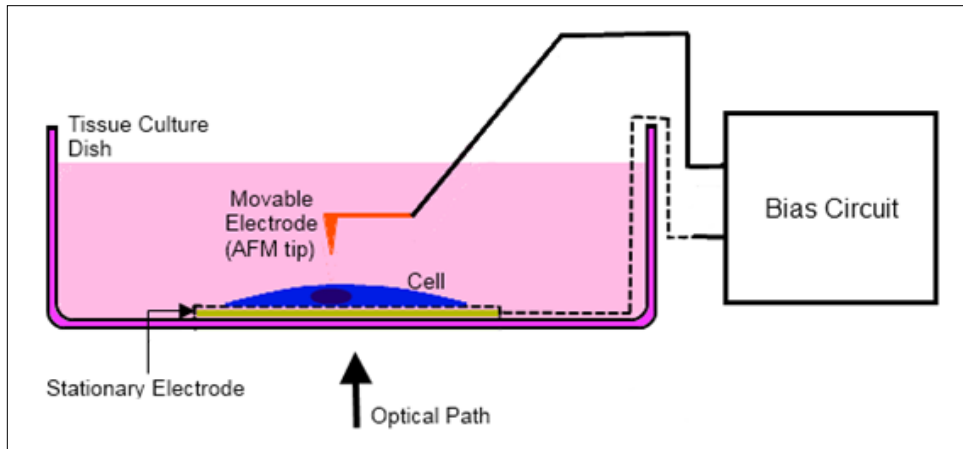
Interests in membrane changes due to disease or exposure to gas/chemicals/toxins

Vertically Directed Growth of Neurons



Spine like structures found in primary neurons growing vertically, appear and disappear randomly with time, present in cell body and growth cone

Is it possible to induce and direct the growth of z-projections?



Test System 2, ITO as stationary electrode, external bias circuit applied isolated biology and electronics,

McNally, H.A., & Abeygunasekara, W.L. An atomic force microscopy system to investigate the effects of external electric fields on neuronal Z-projections. Journal of Neuroscience Methods, in review.

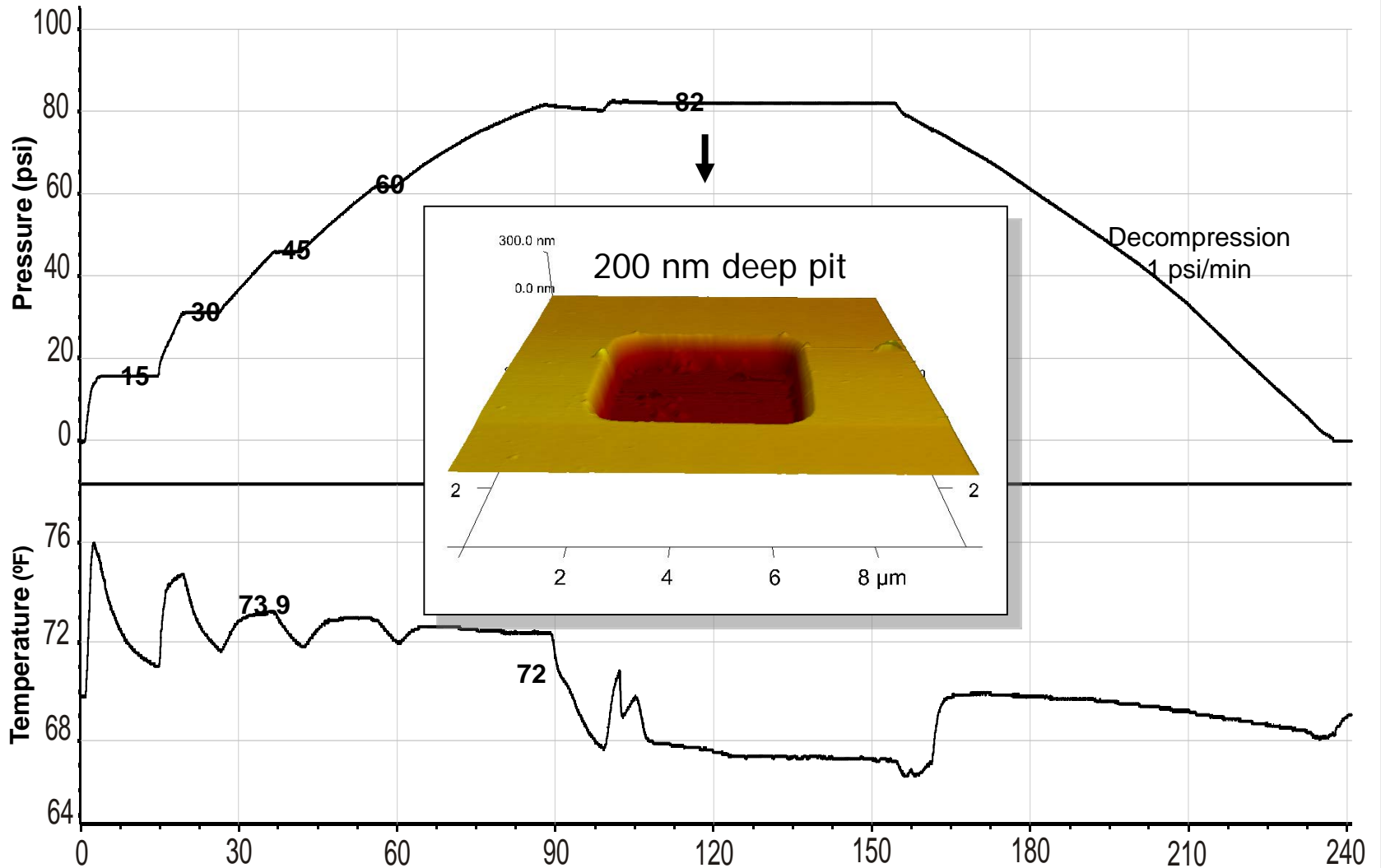
Development and testing of hyperbaric atomic force microscopy (AFM) for biological applications

Dominic D'Agostino & Jay Dean,
University of South Florida, Molecular Pharmacology and
Physiology
Helen McNally Purdue University, Electrical and Computer
Engineering Technology



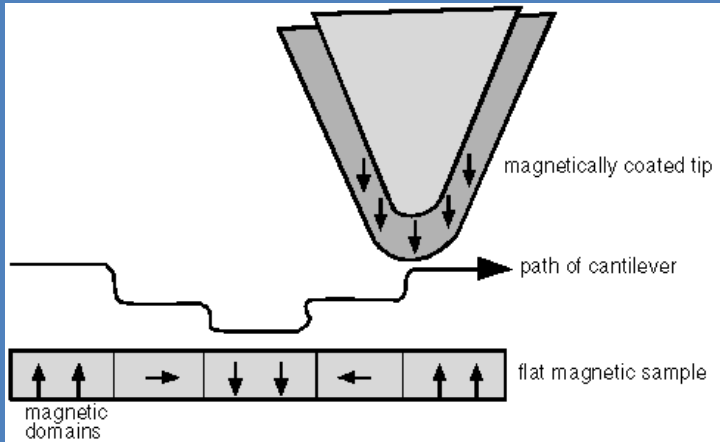
hscweb3.hsc.usf.edu/health/now/?p=96

Pressurization with Helium

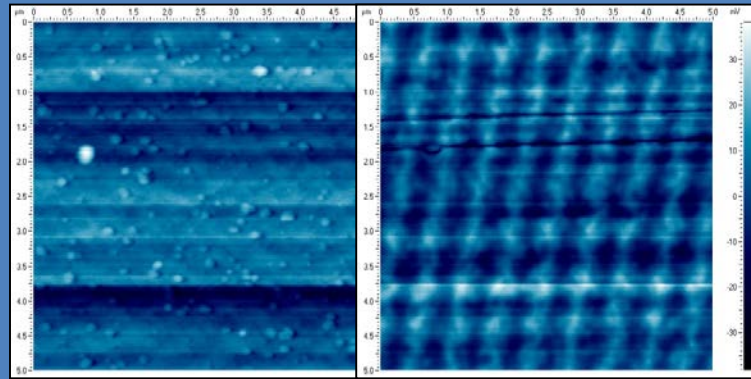


Magnetic Force Microscopy

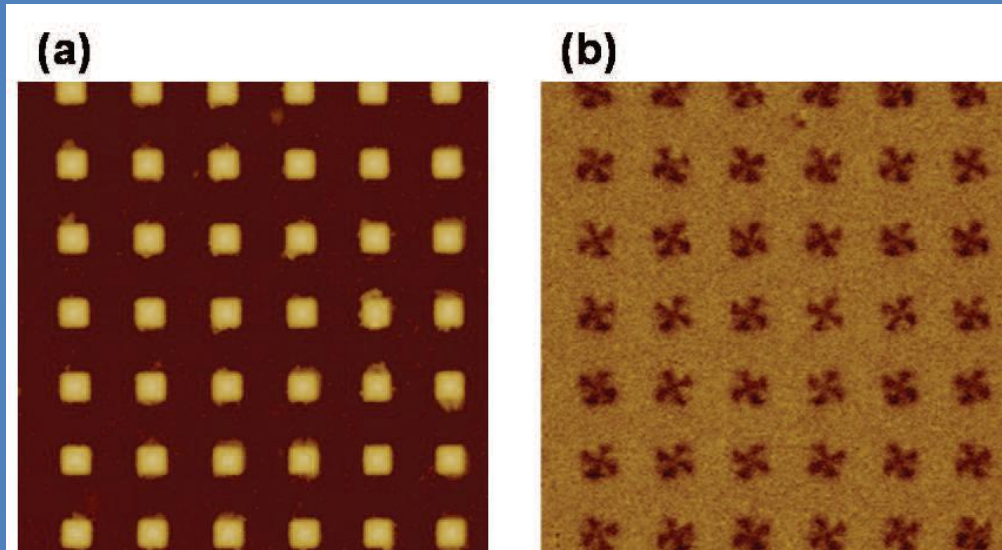
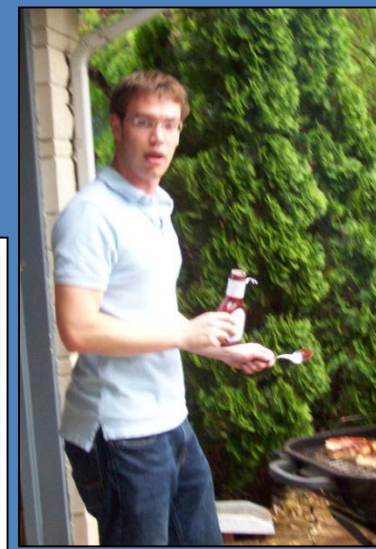
MFM images the spatial variation of magnetic forces on a sample surface.



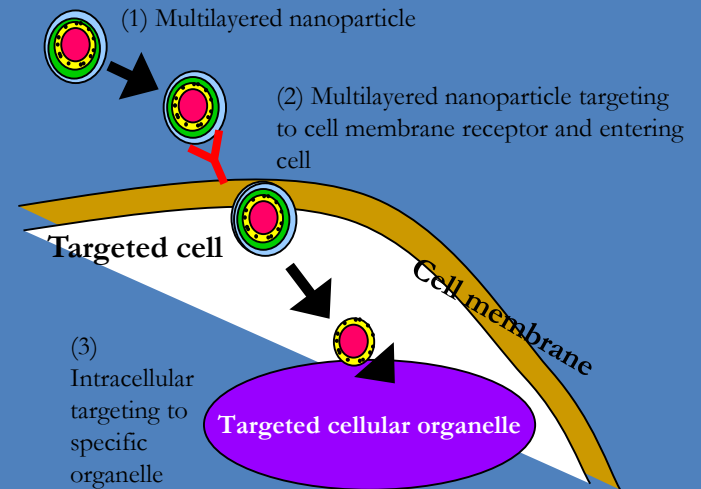
Bruker, Nanosurfaces Division



Topography scan (left) and magnetic scan (right) of magnetic tape taken with Dimension 3100.



Park Systems, (a) AFM and (b) MFM images of 2D patterned arrays of Co dot structure.



Leary and Prow, 2005

(4) Delivery of therapeutic gene

Specific Challenges to the Electro/Magnetic Force Microscopy

- Electric/Magnetic Calibration
- Resolution
- EFM/MFM in fluid
 - magnetic tips with low spring constants
 - magnetic characteristics of the solution
- External Magnetic Field required for particle magnetism
- Sensitivity (detect magnetic nanoparticles inside cells)

Additional Interest in EFM/MFM

- Technique Optimization, resolution and quantification
- Cell-to-Cell Communications
- Cell Signaling
- Neuronal magnetic aspects
- Conducting polymers, 3D scaffolding

Acknowledgements



Current Students:

Graduate

Thomas Fischer

Ti' Air Riggins

Mengying Wang



Undergraduates

Neal Mahajan

Former Students:

Dr. Mirela Mustata – Simmons College

Waranatha Abeygunasekara – Univ. of Peradeniya, Sri Lanka

Tejasvi Parapudi – CoE Purdue

Eric Milligan – Bruker, Santa Barbara, CA

Yen Hseu – Osha Liang, Houston, TX

Collaborators:

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Dr Jay Dean & Dr. Dominic D'Agostino,
University of South Florida

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Purdue Research Foundation

Colleges of Technology and Engineering

Birck Nanotechnology Center



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Thanks a Million!

QUESTIONS AND DISCUSSION

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What we make moves the world forward.

